

INTERNATIONAL STANDARD

**Measurement techniques of piezoelectric, dielectric and electrostatic
oscillators –
Part 3: Frequency aging test methods**





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INTERNATIONAL ELECTROTECHNICAL COMMISSION

**MEASUREMENT TECHNIQUES OF PIEZOELECTRIC,
DIELECTRIC AND ELECTROSTATIC OSCILLATORS –****Part 3: Frequency aging test methods**

FOREWORD

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International Standard IEC 62884-3 has been prepared by IEC technical committee 49: Piezoelectric, dielectric and electrostatic devices and associated materials for frequency control, selection and detection.

The text of this International Standard is based on the following documents:

CDV	Report on voting
49/1248/CDV	49/1272/RVC

Full information on the voting for the approval of this International Standard can be found in the report on voting indicated in the above table.

This document has been drafted in accordance with the ISO/IEC Directives, Part 2.

A list of all parts in the IEC 62884 series, published under the general title *Measurement techniques of piezoelectric, dielectric and electrostatic oscillators*, can be found on the IEC website.

The committee has decided that the contents of this document will remain unchanged until the stability date indicated on the IEC website under "<http://webstore.iec.ch>" in the data related to the specific document. At this date, the document will be

- reconfirmed,
- withdrawn,
- replaced by a revised edition, or
- amended.

A bilingual version of this publication may be issued at a later date.

INTRODUCTION

This document was developed from the works related to IEC 60679-1:2007 (third edition), the measurement techniques of which were restructured into different parts under a new project reference. This document describes the measurement method for frequency aging only.

MEASUREMENT TECHNIQUES OF PIEZOELECTRIC, DIELECTRIC AND ELECTROSTATIC OSCILLATORS –

Part 3: Frequency aging test methods

1 Scope

This part of IEC 62884 describes the methods for the measurement and evaluation of frequency aging tests of piezoelectric, dielectric and electrostatic oscillators, including Dielectric Resonator Oscillators (DRO) and oscillators using FBAR (hereinafter referred to as "Oscillator"). The purpose of those tests is to provide statistical data supporting aging predictions.

2 Normative references

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 60027 (all parts), *Letter symbols to be used in electrical technology*

IEC 60050-561, *International electrotechnical vocabulary – Part 561: Piezoelectric, dielectric and electrostatic devices and associated materials for frequency control, selection and detection*

IEC 60469, *Transitions, pulses and related waveforms – Terms, definitions and algorithms*

IEC 60617, *Graphical symbols for diagrams*, available at <http://std.iec.ch/iec60617>

IEC 60679-1, *Piezoelectric, dielectric and electrostatic oscillators of assessed quality – Part 1: Generic specification*

IEC 62884-1:2017, *Measurement techniques of piezoelectric, dielectric and electrostatic oscillators – Part 1: Basic methods for the measurement*

ISO 80000-1, *Quantities and units – Part 1: General*

3 Terms and definitions, units and symbols

3.1 Terms and definitions

For the purposes of this document, the terms and definitions given in IEC 60679-1 apply.

ISO and IEC maintain terminological databases for use in standardization at the following addresses:

- IEC Electropedia: available at <http://www.electropedia.org/>
- ISO Online browsing platform: available at <http://www.iso.org/obp>